

Agilent 4155C Semiconductor Parameter Analyzer Agilent 4156C Precision Semiconductor Parameter Analyzer

Data Sheet



Introduction Agilent 4155C and 4156C Basic Functions

- Set measurement and/or stress conditions
- Control measurement and/or stress execution
- Perform arithmetic calculations
- Display measured and calculated results on the LCD display
- Perform graphical analysis
- Store and recall measurement setups, and measurement and graphical display data
- Dump to printers or plotters for hardcopy output
- Perform measurement and analysis with built-in instrument BASIC
- Self test, Auto calibration

Configuration

The 4155C and 4156C both come standard with Desktop EasyEXPERT software. A PCbased instrument controller with Desktop EasyEXPERT preinstalled is also included with the standard configuration. You have the option of deleting the controller and cable from your order, but Desktop EasyEXPERT Standard version is always included with both instruments. If you want the Desktop EasyEX-PERT Plus version, you can request the B1541A-002 when you order a 4155C or 4156C. For more information about the Desktop EasyEXPERT Plus, please refer to page 10 of this data sheet.

4155C	4156C
4xMPSMU	4xHRSMU
2xVMU	2xVMU
2xVSU	2xVSU
Desktop EasyEXPERT	Desktop EasyEXPERT

Standard PC-based controller	
and USB/GPIB interface	

41501B (Optional)



¹ Minimum number of installable MPSMU or PGU is two. **SMU: Source Monitor Unit** Display resolution: 6 digits at each current range (0.01fA display resolution at 10pA range)² HRSMU: High Resolution SMU $(1fA/2\mu V \text{ to } 100 \text{mA}/100 \text{V})$ MPSMU: Medium Power SMU $(10 fA/2\mu V to 100 mA/100 V)$ HPSMU: High Power SMU $(10 fA/2 \mu V \text{ to } 1A/200 V)$ VMU: Voltage Monitor Unit $(0.2\mu V resolution in differential$ mode) VSU: Voltage Source Unit PGU: Pulse Generator Unit (1 channel) **GNDU: Ground Unit**

² Accuracy not guaranteed. Minimum guaranteed resolution is 1 fA at 10 pA range.



Hardware

Specification Condition

The "supplemental" information and "typical" entries in the following specifications are not warranted, but provide useful information about the functions and performance of the instruments. The measurement and output accuracy are specified at the rear panel connector terminals when referenced to the Zero Check terminal under the following con-ditions:

- 1. 23° C \pm 5° C (double between 5° C to 18° C, and 28° C to 40° C if not noted otherwise)
- 2. After 40 minutes warm-up
- 3. Ambient temperature change less than ±1° C after auto calibration execution.
- 4. Integration time: medium or long
- 5. Filter: ON (for SMUs)
- 6. Kelvin connection (for HRSMU, HPSMU, and GNDU)
- 7. Calibration period: 1 year

Agilent 4156C Precision Semiconductor Parameter Analyzer

HRSMU (High Resolution SMU) Specifications Voltage Range, Resolution, and Accuracy (HRSMU)

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Voltage Range						
±2V	100µV	±(0.02%+400µV)	$2\mu V$	±(0.01%+200µV)	100mA	
±20V	1mV	±(0.02%+3mV)	20µV	±(0.01%+1mV)	100mA	
±40V	2mV	±(0.025%+6mV)	$40 \mu V$	±(0.015%+2mV)	1	
±100V	5mV	±(0.03%+15mV)	100µV	±(0.02%+5mV)	2	

¹ 100mA (Vout ≤20V), 50mA (20V<Vout≤40V)

² 100mA (Vout ≤20V), 50mA (20V<Vout≤40V), 20mA (40V<Vout≤100V)

Current Range, Resolution, and Accuracy (HRSMU)

Current Range	Set. Reso.	Set. Accuracy	Meas. Reso.	Meas. Accuracy	Max. V
±10pA	10fA	±(4%+400fA) ^{1,2}	1fA	±(4%+20fA+1fA×Vout/100) 1,2	100V
±100pA	10fA	±(4%+400fA) ^{1,2}	1fA	±(4%+40fA+10fA×Vout/100) 1,2	100V
±1nA	100fA	±(0.5%+0.7pA+1fA×Vout) ²	10fA	±(0.5%+0.4pA+1fA×Vout) ²	100V
±10nA	1pA	±(0.5%+4pA+10fA×Vout)	10fA	±(0.5%+2pA+10fA×Vout)	100V
±100nA	10pA	±(0.12%+40pA+100fA×Vout)	100fA	±(0.1%+20pA+100fA×Vout)	100V
±1µA	100pA	±(0.12%+400pA+1pA×Vout)	1pA	±(0.1%+200pA+1pA×Vout)	100V
±10μA	1nA	±(0.07%+4nA+10pA×Vout)	10pA	±(0.05%+2nA+10pA×Vout)	100V
±100µA	10nA	±(0.07%+40nA+100pA×Vout)	$100 \mathrm{pA}$	±(0.05%+20nA+100pA×Vout)	100V
±1mA	100nA	±(0.06%+400nA+1nA×Vout)	1nA	±(0.04%+200nA+1nA×Vout)	100V
±10mA	1µA	±(0.06%+4µA+10nA×Vout)	10nA	±(0.04%+2µA+10nA×Vout)	100V
±100mA	10μΑ	$\pm (0.12\%+40\mu$ A+100nA×Vout)	100nA	±(0.1%+20µA+100nA×Vout)	3

¹The accuracy is applicable when offset cancellation has been performed.

²The offset current specification is multiplied by one of the following factors

depending upon the ambient temperature and humidity

(RH = Relative Humidity)

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	Humidity %	RH
Temperature	5 - 60	60 - 80
5° C to 18° C	×2	×2
18° C to 28° C	×1	×2
28° C to 40° C	×2	×5

³ 100V (Iout≤20mA) 40V (20mA<Iout≤50mA) 20V (50mA<Iout≤100mA)

Vout is the output voltage in volts. Iout is the output current in amps. For example, accuracy specifications are given as \pm % of set/measured value (0.04%) plus offset value (200nA+1nA×Vout) for the 1mA range. The offset value consists of a fixed part determined by the set/measurement range and a proportional part that is multiplied by Vout or Vout/100.

Output terminal/connection:

Dual triaxial connectors, Kelvin (remote sensing)

Voltage/Current Compliance (Limiting):

The SMU can limit output voltage or current to prevent damaging the device under test. Voltage: 0 V to ±100 V Current: ±100 fA to ±100 mA Compliance Accuracy: Same as the current (voltage) settling accuracy.

HRSMU Supplemental Information:

Maximum allowable cable resistance when using Kelvin connection (Force,

Sense): 10 Ω

Typical voltage source output

resistance (Force line/non-Kelvin

connection): $0.2 \,\Omega$

 $Voltage\ measurement\ input\ resistance/$

current source output resistance:

 $\geq 10^{15} \Omega (10 \text{ pA range})$

Current compliance setting accuracy for opposite polarity:

10 pA to 10 nA range: V/I setting accuracy ±12% of range 100 nA to 100 mA range: V/I setting accuracy ±2.5% of range



Agilent 4155C Semiconductor Parameter Analyzer

MPSMU (Medium Power SMU) Specifications Voltage Range, Resolution, and Accuracy (MPSMU)

Voltage Range		Set. Accuracy	Meas. Reso.		Max. Current
±2V	100µV	±(0.03%+900µV+0.3×Iout)	2µV	±(0.02%+700µV+0.3×Iout)	100mA
±20V	1mV	±(0.03%+4mV+0.3×Iout)	$20 \mu V$	±(0.02%+2mV+0.3×Iout)	100mA
±40V	2mV	±(0.03%+7mV+0.3×Iout)	$40 \mu V$	±(0.02%+3mV+0.3×Iout)	1
±100V	5mV	±(0.04%+15mV+0.3×Iout)	$100 \mu V$	±(0.03%+5mV+0.3×Iout)	2

¹100mA (Vout ≤20V), 50mA (20V<Vout ≤40V)

²100mA (Vout ≤20V), 50mA (20V<Vout ≤40V), 20mA (40V<Vout≤100V)

Current Range, Resolution, and Accuracy (MPSMU)

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Current Range	Set. Reso.	Set. Accuracy	Meas. Reso.	Meas. Accuracy	Max. V
±1nA	100fA	±(0.5%+3pA+2fA×Vout)	10fA	±(0.5%+3pA+2fA×Vout)	100V
±10nA	1pA	±(0.5%+7pA+20fA×Vout)	10fA	±(0.5%+5pA+20fA×Vout)	100V
±100nA	10pA	±(0.12%+50pA+200fA×Vout)	100fA	±(0.1%+30pA+200fA×Vout)	100V
±1μA	100pA	±(0.12%+400pA+2pA×Vout)	1pA	±(0.1%+200pA+2pA×Vout)	100V
±10μA	1nA	±(0.12%+5nA+20pA×Vout)	10pA	±(0.1%+3nA+20pA×Vout)	100V
±100µA	10nA	±(0.12%+40nA+200pA×Vout)	100pA	±(0.1%+20nA+200pA×Vout	100V
±1mA	100nA	±(0.12%+500nA+2nA×Vout)	1nA	±(0.1%+300nA+2nA×Vout)	100V
±10mA	1µA	±(0.12%+4µA+20nA×Vout)	10nA	±(0.1%+2µA+20nA×Vout)	100V
±100mA	10µA	±(0.12%+50µA+200nA×Vout)	100nA	±(0.1%+30µA+200nA×Vout)	1

¹ 100 V (Iout ≤20 V), 40 V (20mA<Iout≤50mA), 20V (50mA<Iout≤100mA) Vout is the output voltage in volts. Iout is the output current in amps. For example, accuracy specifications are given as ±% of set/measured value (0.1%) plus offset value (30pA+200fA×Vout) for the 100nA range. The offset value consists of a fixed part determined by the set/ measurement range and a proportional part that is multiplied by Vout.

Output terminal/connection:

Single triaxial connector, non-Kelvin (no remote sensing)

Voltage/Current Compliance (Limiting):

The SMU can limit output voltage or current to prevent damaging the device under test. Voltage: 0 V to ±100 V Current: ±1 pA to ±100 mA Compliance Accuracy: Same as the current (voltage) settling accuracy.

MPSMU Supplemental Information:

Typical voltage source output resistance: 0.3 Ω Voltage measurement input resistance/ current source output resistance: $\geq 10^{13} \Omega$ (1 nA range) Current compliance setting accuracy for opposite polarity: InA to 10 nA range: V/I setting accuracy ±12% of range 100 nA to 100 mA range: V/I setting accuracy ±2.5% of range



VSU and VMU specifications are common to both the 4155C and 4156C

VSU (Voltage Source Unit) Specifications

VSU Output Range:

Voltage Range	Meas. Reso.	Meas. Accuracy
±20V	1mV	$\pm (0.05\% \text{ of setting } \pm 10 \text{mV})^1$
1		

¹ Specification is applicable under no load current. Max. Output Current: 100mA

VSU Supplemental Information:

Output resistance: 0.2Ω (typical) Maximum load capacitance: $10 \mu F$ Maximum slew rate: $0.2 V/\mu s$ Current limit: 120 mA (typical) Output Noise: 1 mV rms (typical)

VMU (Voltage Monitor Unit) Specifications

VMU Differential Mode Range, Resolution, and Accuracy:

Diff V Range		Meas. Accuracy
±0.2V	0.2µV	±(0.03%+10µV+0.3µV×Vi)
±2V	$2\mu V$	±(0.02%+100µV+3µV×Vi)
Marr C		Made Valtages + 20V

Max. Common Mode Voltage: ± 20V

Note: Vi is the input voltage of VMU2 in volts. For example, accuracy specifications are given as \pm % of set/measured value (0.02%) plus offset value (100 μ V+3 μ V×Vi) for the 2V range. The differential mode offset value consists of a fixed part determined by the measurement range and a proportional part that is multiplied by Vi.

VMU Measurement Range, Resolution, and Accuracy:

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Voltage	Meas.	Meas.			
Range	Reso.	Accuracy			
±2V	2μV	±(0.02%+200μV)			
±20V	20μV	± (0.02%+1mV)			

VMU Supplemental Information:

Input Impedance: $\geq 1G \Omega$

Input leakage current (@0 V): ≤500 pA Measurement noise: 0.01% of range

(p-p) (typical) when integration time is 10 PLC

Differential mode measurement noise: 0.005% of range (p-p) (typical) when integration time is short.

Agilent 41501B SMU and Pulse Generator Expander

HPSMU (High Power SMU) Specifications

Voltage Range, Resolution, and Accuracy (HPSMU)

Voltage	Set.	Set.	Meas.	Meas.	Max.
Range	Reso.	Accuracy	Reso.	Accuracy	Current
± 2V	100µV	±(0.03%+900µV)	2μV	±(0.02%+700µV)	1A
± 20V	1mV	±(0.03%+4mV)	20µV	±(0.02%+2mV)	1A
± 40V	2mV	±(0.03%+7mV)	40µV	±(0.02%+3mV)	500mA
±100V	5mV	±(0.04%+15mV)	100µV	$\pm (0.03\% + 5 mV)$	125mA
±200V	10mV	±(0.045%+30mV)	200µV	±(0.035%+10mV)	50mA

Current Range, Resolution, and Accuracy (HPSMU)

Current	Set.	Set.	Meas.	Meas.	Max
Range	Reso.	Accuracy	Reso.	Accuracy	V
±1nA	100fA	±(0.5%+3pA+2fA×Vout)	10fA	±(0.5%+3pA+2fA×Vout)	200V
±10nA	1pA	±(0.5%+7pA+20fA×Vout)	10fA	±(0.5%+5pA+20fA×Vout)	200V
±100nA	10pA	$\pm (0.12\%+50 \text{pA}+200 \text{fA}\times \text{Vout})$	100fA	±(0.1%+30pA+200fA×Vout	200V
±1μA	100pA	±(0.12%+400pA+2pA×Vout)	1pA	±(0.1%+200pA+2pA×Vout)	200V
$\pm 10 \mu A$	1nA	±(0.12%+5nA+20pA×Vout)	10pA	±(0.1%+3nA+20pA×Vout)	200V
±100µA	10nA	±(0.12%+40nA+200pA×Vout)	100pA	±(0.1%+20nA+200pA×Vout	200V
±1mA	100nA	±(0.12%+500nA+2nA×Vout)	1nA	±(0.1%+300nA+2nA×Vout)	200V
±10mA	1µA	±(0.12%+4µA+20nA×Vout)	10nA	±(0.1%+2µA+20nA×Vout)	200V
$\pm 100 \text{mA}$	10μΑ	±(0.12%+50µA+200nA×Vout)	100nA	$\pm (0.1\%+30\mu$ A+200nA×Vout)	1
±1A	100µA	±(0.5%+500µA+2µA×Vout)	1µA	±(0.5%+300µA+2µA×Vout)	2

 1 200V (Iout ${\leq}50 \text{mA}$), 100V (50mA<Iout {\leq}100 \text{mA})

 $^{2}200V \text{ (Iout } \leq 50 \text{mA}\text{)}, 100V \text{ (}50 \text{mA}\text{<}\text{Iout} \leq 125 \text{mA}\text{)}, 40V \text{ (}125 \text{mA}\text{<}\text{Iout} \leq 500 \text{mA}\text{)}, 20V \text{ (}500 \text{mA}\text{<}\text{Iout} \leq 1 \text{mA}\text{)}$

Vout is the output voltage in volts. Iout is the output current in amps. For example, accuracy specifications are given as $\pm\%$ of set/measured value (0.1%) plus offset value (30pA+200fA×Vout) for the 100nA range. The offset value consists of a fixed part determined by the set/measurement range and a proportional part that is multiplied by Vout.

Output terminal/connection:

Dual triaxial connectors, Kelvin (remote sensing)

Voltage/Current Compliance (Limiting):

Voltage: 0V to ±200V Current: ±1pA to ±1A Compliance Accuracy: Same as the current (voltage) settling accuracy.

HPSMU Supplemental Information:

Maximum allowable cable resistance when using Kelvin connection: Force: 0.7Ω (100mA to 1A) Force: 10Ω (≤ 100 mA) Sense: 10Ω Typical voltage source output resistance (Force line/non-Kelvin connection): 0.2Ω Voltage measurement input resistance/current source output resistance: $\geq 10^{13} \Omega$ (1nA range) Current compliance setting accuracy for opposite polarity: 1nA to 10nA range: V/I setting accuracy ±12% of range

100nA to 1A range: V/I setting accuracy ±2.5% of range



PGU (Pulse Generator Unit) Specifications

Modes: Pulse or constant Amplitude: 0Vp-p to 40Vp-p Window: -40.0V to +40.0V Maximum current: ±100mA ±200mA (pulse width: ≤1ms, average current 100mA) Pulse width: 1.0µs to 9.99s Minimum resolution: 100ns Pulse period: 2.0µs to 10.0s Minimum resolution: 100ns Delay: 0s to 10s Minimum resolution: 100ns Transition time: 100ns to 10ms Minimum resolution: 1ns Output impedance: 50Ω or low impedance ($\leq 1\Omega$) Burst count range: 1 - 65535 Pulse parameter accuracy: Period: $\pm(2\% + 2ns)$ Width: $\pm(3\% + 2ns)$

Delay: ±(2% +40ns) Transition time: ±(5% +10ns) Trigger output: Level: TTL Timing: Same timing and width as PGU1 pulse output

PGU Supplemental Information:

Overshoot: $\leq \pm 5\%$ of amplitude ± 10 mV (50Ω output impedance to 50Ω load) Pulse width jitter: 0.2% + 100ps Pulse period jitter: 0.2% + 100ps Maximum slew rate: $100V/\mu s$ (50Ω output impedance to 50Ω load) Noise: 0.2% of range (@ DC output)

MPSMU Specifications

Same as 4155C MPSMU.

GNDU (Ground Unit) Specifications:

Output Voltage: 0V ±100µV Maximum sink current: 1.6A Output terminal/connection: Single triaxial connector, Kelvin (remote sensing)

GNDU Supplemental Information

Load Capacitance: $\leq 1 \mu F$ Cable resistance: Force $\leq 1\Omega$ Sense $\leq 10\Omega$

HRSMU, MPSMU, HPSMU

Supplemental Information

Maximum capacitive load: 1000pF Maximum guard capacitance: 900pF Maximum shield capacitance: 5000pF Maximum guard offset voltage: ±1mV Noise characteristics (typical, Filter: ON): Voltage source noise: 0.01% of V

range (rms)

Current source noise: 0.1% of I range (rms)

Voltage monitor noise: 0.02% of V range (p-p)

Current monitor noise: 0.2% of I

Output overshoot (typical, Filter: ON):

Voltage source: 0.03% of V range

Current source: 1% of I range

Range switching transient noise (typical, Filter: ON):

Voltage ranging: 250mV

Current ranging: 10mV

Maximum slew rate: 0.2V/µs

Pulse/DC Output Voltage and Accuracy (PGU)

Set	Voltage		
Parameter	Range	Resolution	Accuracy ¹
Base	±20V	4mV	±(1% of Base +50mV +1% of Pulse)
	±40V	8mV	±(1% of Base +50mV +1% of Pulse)
Pulse	±20V	4mV	±(3% of Base +50mV)
	±40V	8mV	±(3% of Base +50mV)

Note: DC output is performed by the Base Parameter.

 1Accuracy is specified at leading edge - trailing edge = $1\mu s$

Pulse Range and Pulse Parameter (PGU)

Range	Period	Width	Delay	Set resolution
1	2μs -100μs	1μs - 99.9μs	0 - 100µs	0.1µs
2	100µs - 1000µs	1μs - 999μs	0 - 1000µs	1µs
3	1ms - 10ms	0.01ms - 9.99ms	0 - 10ms	10µs
4	10ms - 100ms	0.1ms - 99.9ms	0 - 100ms	100µs
5	100ms - 1000ms	1ms - 999ms	0 - 1000ms	1ms
6	1s - 10s	0.01s - 9.99s	0 - 10s	10ms

Note: Pulse width is defined when leading time is equal to trailing time. PGU2 must be set in the same range as PGU1.

Leading/Trailing Edge Times (PGU)

Range	Set Resolution`	Accuracy
100ns - 1000ns	1ns	$\pm(5\% + 10ns)$
0.5µs - 10µs	10ns	$\pm(5\% + 10 \text{ns})$
5.0µs - 100µs	100ns	$\pm(5\% + 10 \text{ns})$
50µs - 1000µs	1µs	$\pm(5\% + 10ns)$
0.5ms - 10ms	10µs	±(5% + 10ns)

Restrictions:

Pulse width < Pulse Period, Delay time < Pulse period, Leading time < Pulse width $\times 0.8$

Trailing time < (Pulse period - Pulse width) $\times 0.8$

Period, width, and delay of PGU1 and PGU2 must be in the same range. Leading time and trailing time for a PGU must be in the same range.

Capacitance Calculation Accuracy (Supplemental Data)

Accuracy is derived from the current range, voltage range, capacitance measurement and leakage current measurement integration times, and the guard capacitance of cabling and step voltage. The information in the chart below is based on the following conditions: Voltage Range ±20V; Voltage Step: 100mV; Guard Capacitance : 100pF; Equivalent parallel resistance of DUT: $1\times10^{15}\Omega$. The ratio of integration times for capacitance measurement and leakage current measurement is 1:1.

HRSMU

Current Range	Integration Time	Max. Meas. Value	Resolution	Accuracy Reading %	Offset
10n 4 /	0.5sec	100pF/1pF	5fF	4.2	70fF
10pA/ 100pA	1sec	2pF/20pF	10fF	4.3	$90 \mathrm{fF}$
тора	2sec	$76 \mathrm{pF} / 760 \mathrm{pF}$	20fF	4.3	$130 \mathrm{fF}$
	0.1sec	700pF	10fF	0.84	160fF
1nA	0.5sec	4.5nF	$40 \mathrm{fF}$	0.85	280fF
	2sec	18nF	200fF	0.93	740fF
	0.1sec	7nF	10fF	0.84	200fF
	0.5sec	45nF	40fF	0.85	440fF
10nA	2sec	180nF	200fF	0.93	$1.4 \mathrm{pF}$
	10sec	940nF	$1 \mathrm{pF}$	1.3	$6.2 \mathrm{pF}$

MPSMU

Current	Integration Time	Max. Meas. Value	Resolution	Accuracy Reading %	Offset
	0.1sec	700pF	10fF	0.91	170fF
1nA	0.5sec	4.5nF	$40 \mathrm{fF}$	0.94	$340 \mathrm{fF}$
	2sec	18nF	200fF	1.0	$1 \mathrm{pF}$
	0.1sec	7nF	10fF	0.91	180fF
10nA	0.5sec	45nF	40fF	0.94	480fF
	2sec	180nF	200fF	1.0	1.6pF
	10sec	940nF	$1 \mathrm{pF}$	1.6	7.6pF

Current compliance must be smaller than the current range. The capacitance of the DUT and measurement path must be smaller than the maximum measurement value.

Functions

Measurement Setup

Setting

- Fill-in-the-blanks using front-panel or full-size external keyboard
- Load settings from floppy disk or via the LAN port
- Program using internal Instrument BASIC or via GPIB
- HELP Function
- Library: Default measure setup, Vce-Ic, Vds-Id, Vgs-Id, and Vf-If are predefined softkeys
- User-defined measurement setup library
- Auto file load function on power-up

Measurement

The 4155C and 4156C can perform dc or pulsed force/measure, and stress force. For dc, voltage/ current sweep and sampling (time domain) measurements are available.

Voltage/Current Sweep Measurement Characteristics

Each SMU and VSU can sweep using VAR1 (primary sweep), VAR2 (subordinate sweep), or VAR1 (synchronous sweep).

VAR1

Primary sweep controls the staircase (dc or pulsed) voltage or current sweep.

Maximum number of steps: 1001 for one VAR1 sweep.

Sweep type: linear or logarithmic Sweep direction: Single or double sweep Hold time: Initial wait time or wait time after VAR2 is set: 0 to 655.35s with 10ms resolution

Delay time: Wait time from VAR1 step to the start of the measurement: 0 to 65.535s with 100µs resolution

VAR2

Subordinate linear staircase or linear pulsed sweep. After primary sweep is completed, the VAR2 unit output is incremented.

Maximum number of steps: 128

VAR1¹

Staircase or pulse sweep synchronized with the VAR1 sweep. Sweep is made with a user specified ratio and offset value. VAR1ⁱ output is calculated as VAR1ⁱ = $a \times VAR1 + b$, where "a" is the user specified ratio and "b" is the user specified offset value.

CONSTANT

A source unit can be set as a constant voltage or current source depending on the unit.

PULSE

One of the SMUs can be set as a pulse source.

Pulse width: 0.5ms to 100ms, 100µs resolution.

Pulse period: 5ms to 1s (3pulse width + 4ms), 100 μs resolution.

SMU pulse setting accuracy (supplemental information, at fixed range measurement except multichannel measurement):

Width: 0.5% + 50µs

Period: 0.5% + 100µs

Trigger output delay for pulsed measurement: 0 - 32.7ms with 100µs resolution (< pulse width).

Sampling (Time Domain) Measurement Characteristics

Displays the time sampled voltage/

current data versus time. Max. sampling points: 10,001 (linear)

Sampling mode: linear, log, and

thinned-out

Note: The thinned-out mode is similar to reverse-log sampling. Sampling measurement continues by thinning out older data until the sampling completion condition is satisfied.

Sampling interval range and resolution: Linear scale (auto mode):

60μs to 480μs range: 20μs resolution 480μs to 1s range: 80μs resolution

1s to 65.535s range: 2ms resolution Linear scale (no limit mode), log

scale, and thinned-out modes:

560μs (720μs at thinned-out mode) to 1s range: 80μs resolution

1s to 65.535s range: 2ms resolution

Note: The following conditions must be set when initial interval is less than 2ms.

• Number of measurement channels: 1

Measurement ranging: fixed range
Stop condition: disable

Hold time:

Initial wait time: 0.03s to 655.35s, 100µs resolution

Sampling measurement stop condition: A condition to stop the sampling can be defined.

Sampling interval setting accuracy (supplemental data):

0.5% + 10µs (sampling interval ≤480µs) 0.5% + 10µs (480µs ≤sampling interval <2ms)

0.5% + 100µs (2ms ≤sampling interval)

C-V Measurement Characteristics

Capacitance is a calculated value derived from the following equation:

 $C = \frac{\Delta Q}{\Delta V}$

 ΔQ is the change in charge when ΔV , the step voltage, is applied by the SMU; ΔQ is derived from the measurement current (amps) and the integration time (seconds).

Maximum Measurable Value

Maximum measurable value depends on the current range, integration time, and step voltage (refer to the chart in supplemental data).

Capacitance Calculation Accuracy

Accuracy is dependent on accuracy of the current measurement and voltage measurement and the stray capacitance and leakage current of measurement path, etc. (Refer to the chart in supplemental data).

Zero Offset

Cancels stray capacitance of the fixtures and test leads.

Leakage Current Compensation

Cancels the influence of the leakage current to the capacitance measurement.

Stress Force Characteristics

SMU, VSU, and PGU output can be forced for the user specified period. Stress time set range: 500µs to 31,536,000s (365 days)

Resolution:

100µs (500µs ≤stress time ≤10s) 10ms (10s <stress time ≤31,536,000s) Burst pulse count: 1 - 65,535 (PGU only) Trigger: The 4155C and 4156C output a gate trigger while stress channels are forcing stress.

Knob Sweep

In knob sweep mode, sweep range is controlled instantaneously with the front-panel rotary knob. Only the Channel Definition page need be defined.

Standby Mode

SMUs in "Standby" remain programmed to their specified output value even as other units are reset for the next

measurement.

Other Characteristics

Measurement Control: Single, append, repeat, and stop

Stress Control: Stress force and stop SMU Setting Capabilities: Limited autoranging, voltage/current compliance, power compliance, automatic sweep abort functions, self-test, and selfcalibration.

Arithmetic and Analysis Functions

Arithmetic Functions User Functions

Up to six USER FUNCTIONS can be defined using arithmetic expressions. Measured data and analyzed variables from graphics analysis (marker, cursor, and line data) can be used in the computation. The results can be displayed on the LCD.

Arithmetic Operators

+, -, *, /, ^, LGT (logarithm, base 10), LOG (logarithm, base e), EXP (exponent), DELTA, DIFF (differential), INTEG (integration), MAVG (moving average), SQRT, ABS (absolute value), MAX, MIN, AVG (averaging), COND (conditional evaluation).

Physical Constants

Keyboard constants are stored in memory as follows:

q:Electron Charge, 1.602177 E-19 C k:Boltzman's Constant, 1.380658 E-23 ε (e): Dielectric Constant of Vacuum, 8.854188 E-12

Engineering Units

The following unit symbols are also available on the keyboard: f (10⁻¹⁵), p (10⁻¹²), n (10⁹), u or m (10⁸), m (10³), K (10³), M (10⁶), G (10⁹)

Analysis Capabilities Overlay Graph Comparison

A graphics plot can be stored and later recalled as an overlay plane. Four overlay planes can be stored. One plane can be overlaid onto the current data.

Marker

Marker to min/max, interpolation, direct marker, and marker slip

Cursor

Long and short, direct cursor.

Line

Two lines, normal mode, grad mode, tangent mode, and regression mode.

Scaling

Auto scale and zoom.

Data Variable Display Up to two user defined parameters can be displayed on the graphics screen.

Read Out Function

The read out functions are built-in functions for reading various values

related to the marker, cursor, or line.

Automatic Analysis Function

On a graphics plot, the markers and lines can be automatically located using the auto analysis setup. Parameters can be automatically determined using automatic analysis, user function, and read out functions.

User Variable

Display the data on the LCD via GPIB or instrument BASIC.

Output

Display

Display Modes

Graphics and list.

Graphics Display

X-Y or X-Y1/Y2 plot of source current/ voltage, measured current/voltage, time, or calculated USER FUNCTION data.

List Display

Measurement data and calculated USER FUNCTION data are listed in conjunction with VAR1 step number or time domain sampling step number. Up to eight data sets can be displayed.

Display

8.4-inch diagonal color active matrix LCD, 640 dot (H) $\stackrel{<}{}$ 480 dot (V). More than 99.99% of the pixels on an LCD are active.

Hard Copy Functions

Graphics Hard Copy

Measured data and all data appearing on the LCD can be output via GPIB, parallel printer port, or network interface to supported HP plotters or printers. PCL, HR PCL (high-resolution PCL), and HP-GL formats are supported (selectable).

Text Hard Copy

Print out setup information or measured data list as ASCII text via GPIB, parallel printer port, or network interface to supported HP plotters or printers. PCL, HR PCL, and HP GL formats are supported (selectable).

Hard Copy File

Hard copy output can be stored to an internal or external mass storage device instead of sending it to a printer or plotter. The data can be stored in PCL, HR PCL, TIFF, HR TIFF (highresolution TIFF), or HP GL formats.

Hard Copy via Network Interface

The network interface has lpr client capability.

High-Resolution (HR) Mode

This file mode is available for cases where an extremely clean print-out or plot is desired. Note: High-resolution mode takes significantly greater CPU time to generate so its use is

greater CPU time to generate, so its use is recommended for final reports only.

Data Storage

Mass storage device: Built-in 3.5-inch floppy disk drive Media: 3.5-inch 2HD or 2DD diskette Format type: HP LIF and DOS User area: 1.44Mbyte (2HD) or 720Kbyte (2DD)

File types:

Auto start program file, initial setup file, measurement setup file, mea surement setup/result file, stress setup file, customize file, hard copy data file, and Instrument BASIC program and data file.

Format of data made by the HP BASIC program:

Data made by the HP BASIC program and data made by the Instrument BASIC program are compatible. Network mass storage device:

An NFS mountable mass storage device File types:

Auto start program file, initial setup file, measurement setup file, measurement setup/result file, stresS setup file, customize file, and hard copy data file.

Maximum number of files allowed per directory on network mass storage device: 199

Data storage (supplemental data): 2HD DOS format:

Available bytes: 1457K (byte) File size:

Measurement setup: 3843 (byte) Stress setup: 601 (byte) Measurement setup/result

(Typical data): 15387 (byte) (VAR1: 101, VAR2: 5)

Customized system setup: 1661 (byte) Hardcopy data: 30317 (byte)

(Monochrome PCL 75DPI file) Hardcopy data: 38702 (byte)

(monochrome TIFF file)

Note: For LIF format, the total number of files is limited to 199.

Repeating and Automating Test

Instrument Control

Agilent 4155C and 4156C function control:

Internal or external computer controls the 4155C and 4156C functions via the GPIB interface

Command sets:

SCPI command set

Agilent FLEX command set

Agilent 4145B command set

Program Memory:

Using the Agilent FLEX command set, the user can store program code in the 4155C or the 4156C. The maximum number of subprograms is 255 (8 bit).

External instrument remote control: Control external equipment via the GPIB interface.

Instrument BASIC

Instrument BASIC is a subset of HP BASIC. Functions:

r unctions:

Arithmetic operation, binary opera tion, string manipulation, logical operation, array operation, program flow control, event-initiated branch ing, program editing and debugging support, mass storage operation, instrument control, real-time clock, softkey operation, and graphics. Agilent 4145B automatic sequence program (ASP) typing aid:

4145B ASP-like syntax softkeys are available in instrument BASIC. A 4145B ASP file cannot be read by the 4155C or 4156C. Remote control:

Instrument BASIC is remote controllable from an external computer via the GPIB interface.

Instrument BASIC memory area (supplemental data):

Program (text) area: 16K (byte) Variable/stack area: 500K (byte)

Common variable area: 600K (byte) Note: The memory size for common variable is decreased when hard copy or disk operation is performed.

Trigger

Input:

External trigger input starts a sweep or sampling measurement or can be used as a trigger input for continuing an Instrument BASIC program. Input Level:

Input Level

TTL level, negative or positive edge trigger

Output:

External edge trigger outputs can be generated by the start of a sweep measurement, the start of each sweep step in a staircase sweep, the start of each pulse leading edge for an SMU in pulse mode, and the issuance of an an IBASIC trigger out command execution. In addition, you can set the trigger signal to be active during the Stress Force State. If you have a 41501A/B with PGU option, you can output a synchronized trigger output through the 41501A/B trigger output. Output Level:

TTL level, negative or positive logic

4145B Data Compatibility and Syntax Commands Setup and data file

Measurement setup and data from the 4145B can be loaded.

GPIB program

GPIB programs for the 4145B can be used when the 4145B command set is selected.

Note: There is a possibility that GPIB programs for the 4145B will need to be modified.

Interfaces

GPIB interface: SH1, AH1, T6, L4, SR1, RL1, PP0, DC1, DT1, C1, C2, C3, C4, C11, E2 Parallel interface: Centronics RJ45: Ethernet IEEE 802.3 10BASE-T for a 10Mbps CSMA/CD local area network External keyboard: Compatible PC-style 101-key keyboard (mini DIN connector) Interlock and LED connector R-BOX control connector Trigger in/out SMU/PGU selector control connector (41501B)

Sample Application

Programs

Flash EEPROM test TDDB Constant I (Electromigration test) V-Ramp test J-Ramp test SWEAT GO/NO-GO test HCI degradation test Charging pump test

Sample VEE Program

Vth measurement using the 4155C or 4156C, the E5250A, and a wafer prober.

VXI plug&play Drivers

VXI plug&play drivers for the 4155C and 4156C

Supported VXI *plug&play* operating systems:

Microsoft Windows 95, 98, NT, 2000 Professional, and XP Professional

Format

Tree-structured function panel. Panel mode for hardware configuration and manual parameter setting. Parameter mode for variable definition and I/O configuration.

General Specifications

Temperature range

Operating:

+10°C to +40°C (if using floppy disk drive) +5°C to +40°C (if not using floppy

disk drive)

Storage: -22°C to +60°C

Humidity range

Operating:

20% to 80% RH, non-condensing and wet bulb temperature ≤29°C (if using floppy disk drive)

15% to 80% RH, non-condensing and wet bulb temperature ≤ 29 °C (if not

using floppy disk drive)

Storage: 5% to 90% RH , non-condensing and wet bulb temperature ${\leq}39\,^{\circ}\mathrm{C}$

Altitude

Operating: 0 to 2,000 m (6,561 ft) Storage: 0 to 4,600 m (15,091 ft)

Power requirement

 $90\mathrm{V}$ to $264\mathrm{V},\,47$ to $63~\mathrm{Hz}$

Maximum VA

4155C and 4156C: 450VA 41501B: 350 VA

Regulatory Compliance

EMC: EN 61326-1:+A1, AS/NZS 2064.1 Safety:

CSA C22.2 NO.1010.1 (1992), IEC 61010-1:+A2/EN 61010-1:+A2 UL3111-1:1994 Certification: CE, CSA, NRTL/C, C-Tick

Dimensions

4155C and 4156C: 235mm H × 426mm W × 600mm D 41501B: 190mm H × 426mm W × 600mm D

Weight (approx.)

4155C and 4156C: 21kg 41501B: 16kg (option 412, HPSMU + 2 × PGU)

4155C and 4156C

Furnished Accessories

Triaxial cable, 4 ea. (4155C) Kelvin triaxial cable, 4 ea. (4156C) Coaxial cable, 4 ea. Interlock cable, 1 ea. Keyboard, 1 ea. User manual, 1 set Sample application program disk, 1 ea. Sample VEE program disk, 1 ea. VX*Iplug&play* drivers disk for the 4155C and 4156C, 1 ea. VX*Iplug&play* drivers disk for the

E5250A, 1 ea. LAN Interface Test Adapter, 1 ea.

Accessory Specifications

Specification Condition

The "supplemental information" and "typical" entries in the following specifications are not warranted, but provide useful information about the functions and performance of the instruments $(23^{\circ}C \pm 5^{\circ}, 50\% \text{ RH}).$

16440A SMU/Pulse Generator Selector

The 16440A switches either an SMU or PGU to the associated output port. You can expand to 4 channels by adding an additional 16440A. The channel 1 PGU port provides a "PGU OPEN" function, which can disconnect the PGU by opening a semiconductor relay. The 16440A cannot work without two pulse generator units of the 41501A/B (SMU and Pulse Generator Expander). Channel configurations: Two channels (CH1, CH2) CH1: INPUT ports: 2 (SMU and PGU, PGU port has additional series semiconductor relay) OUTPUT port: 1 CH2: INPUT ports: 2 (SMU and PGU) OUTPUT port: 1

Voltage and Current Range

Input port	Max. V	Max. I
SMU	200V	1.0A
PGU	40V	0.2A (AC Peak)

Supplemental Information (at 23°C ± 5°C, 50%RH)

SMU port leakage current: < 100fA @100V SMU port residual resistance (typical): 0.2Ω SMU port stray capacitance (typical) @1MHz): Force \leftrightarrow Common: 0.3pF Force \leftrightarrow Guard: 15pF Guard \leftrightarrow Common: 130pF PGU port residual resistance: 3.4 Ω PGU port OFF capacitance (typical): 5pF PGU port OPEN capacitance (typical): 700pF (@ 1MHz, Vin - Vout = 0V)

PGU port signal transfer characteristics

Overshoot: < 5% of pulse amplitude (@20ns leading and trailing time, 50Ω pulse generator source impedance, 50pF and $1M\Omega$ in parallel load).

General Specifications

Dimensions:

50mm H \times 250mm W \times 275mm D Approximate weight: 1.1kg

16441A R-BOX

The 16441A R-BOX adds a selectable series resistor to the SMU output. You can select the resistor from the setup page, and the voltage drop due to the series resistor is automatically compensated for in the measurement result. Measurement limitations with the 4155C and 4156C and R-BOX:

If you measure device characteristics including negative resistance over $1M\Omega$ with the 4155C/4156C and R-BOX, there is a possibility that they cannot be measured. There is a possibility that the 4155C and 4156C cannot perform measurements because of DUT oscillations even with the R-BOX. Whether oscillation occurs or not depends upon the DUT and measurement conditions.

Number of SMU channels that can add a resistor: 2

Resistor values:

 $1M\Omega$, $100k\Omega$, $10k\Omega$, 0Ω (each channel)

Resistance accuracy:

 $\begin{array}{l} 0.3\% \,({\rm at}\, 23\,^{\circ}{\rm C}\, \pm 5\,^{\circ}{\rm C}, \, {\rm between\ input-}\\ {\rm output\ terminal})\\ {\rm Maximum\ voltage:}\, 200V\\ {\rm Maximum\ current:}\,\, 1A\,\,(0\Omega\,\, {\rm selected})\\ {\rm Kelvin\ connection:}\,\, {\rm Kelvin\ connection}\\ {\rm is\ effective\ only\ when\ }0\Omega \,\, {\rm is\ selected}. \end{array}$

Supplemental Information (at 23°C ± 5°C, 50%RH)

Leakage current: <100fA @ 100V

General Specifications

Dimensions: 72mm H \times 250mm W \times 270mm D Approximate weight: 1.6kg

16442A Test Fixture

Channel Information

SMIL 6 channels (1 triaxial connector per channel) 3 channels (1 Kelvin triaxial connector per channel) VSU: 2 channels (1 BNC connector per channel) VMU: 2 channels (1 BNC connector per channel) PGU: 2 channels (1 BNC connector per channel) GNDU: 1 channel (1 triaxial connector) **INTLK: 6-pin connector Supplemental Information**

(at 23°C ± 5°C, 50% RH) SMU channel:

Leakage current: 10pA max @200V (Force or Sense \leftrightarrow Common) Stray capacitance: 15pF max (Force or Sense \leftrightarrow Common) Stray capacitance: 3pF typical (Force or Sense \leftrightarrow Other SMU) Residual resistance: $60m\Omega$ typical (Force, Sense) Guard capacitance: 70pF max (Force or Sense \leftrightarrow Guard) VSU channel residual resistance: $60 \text{m}\Omega$ typical VMU channel residual resistance: $60m\Omega$ typical PGU channel characteristic impedance: $50 \mathrm{m}\Omega$ typical GNDU channel residual resistance: $40m\Omega$ typical (Force, Sense) **General Specifications** Temperature range: Operating: +5°C to +40°C Storage: -40° C to $+70^{\circ}$ C Humidity range; Operating: 5% to 80% RH

(no condensation)

Storage: 5% to 90% RH at 65°C

(no condensation)

Dimensions:

140 mm H \times 260 mm W \times 260 mm D Weight (approx.): 2.5kg

Agilent Desktop EasyEXPERT Software

Introduction

Agilent Desktop EasyEXPERT software makes every user a parametric test expert. The Microsoft® Windows®-based interface is familiar, even to new engineers who have limited experience using parametric measurement instruments. Its unique task-based approach enables the user to focus on the real task-at-hand (device characterization) without having to be a specialist at using the instrument hardware. Desktop EasyEXPERT supports all aspects of parametric test, from basic manual measurements to test automation across a wafer in conjunction with a semiautomatic wafer prober.

Features and benefits

Large application test library

Desktop EasyEXPERT comes with more than 230 application tests conveniently organized by device type, application, and technology. Many of these application tests will run on the 4155 and 4156 without modification. You also can easily edit and customize the furnished application tests to fit your specific needs.

Offline capability

Desktop EasyEXPERT can run in either online or offline mode. In offline mode you can perform tasks such as analyzing data and creating new application tests. This frees up your existing analyzer from being needed for development work and enables you to use it for its primary purpose: making measurements.

GUI-based classic test mode

Desktop EasyEXPERT offers a classic test mode that maintains the look, feel, and terminology of the 4155/4156 user interface. In addition, it improves the 4155/ 4156 user interface by taking full advantage of the Windows GUI features.

Easy test sequencing

A GUI-based Quick Test mode lets you to perform test sequencing without programming. You can select, copy, rearrange and cutand-paste any application tests with a few simple mouse clicks. Once you have selected and arranged your tests, simply click on the measurement button to begin running an automated test sequence.

Prober control

All popular semiautomatic wafer probers are supported by Desktop EasyEXPERT. You can define wafer, die and module information for probing across an entire wafer. You can also combine wafer prober control with either Quick Test mode or an application testbased test sequence to perform multiple testing on various devices across the wafer.

Automatic data export

Desktop EasyEXPERT has the ability to automatically export measurement data in real time, in a variety of formats. You can save data to any drive connected to the PC. If you wish, you can export data to a network drive and view test results on your desktop PC at the same time your instruments are performing testing in the lab.

Software Functions

Operation mode

Application test mode, Classic test mode, Quick test mode

Key Functions

- Categorized and predefined application library
- Device definition
- Measurement parameter settings
- Save/Recall My Favorite Setups
- Define/customize application library
- Execute measurement (Single/ Repeat/Append)
- Quick test execution
- Save/Recall measurement data and settings

- Test result data management
- Import/Export device definition, measurement settings, my favorite setup, measurement data, and application library
- Graph plot display/analysis/ printing
- Switching matrix control
- Workspace management

Application Library

Category:

Sample test definitions for the following applications. They are

subject to change without notice. Structure, CMOS, Bipolar (BJT), TFT, Discrete, Nanotechnology, Utility

Supported 4155/4156 Functionality

Desktop EasyEXPERT Standard version • Staircase Sweep

Desktop EasyEXPERT Plus version

The following additional functions are supported.

- I/V-t Sampling except Thinnedout and Logarithmic modes
- VSU/VMU except differential voltage measurement using VMU
 PGU (41501B)

Each SMU can sweep using VAR1 (primary sweep), VAR2 (secondary sweep), or VAR1 (synchronous sweep).

Staircase Sweep Measurement Mode

Forces swept voltage or current, and measures DC voltage or current. A second channel can be programmed to output a pulsed bias voltage or current. A third channel can be synchronized with the primary sweep channel as an additional voltage or current sweep source.

Number of Steps for VAR1 and VAR1: 1 to 1001

Number of Steps for VAR1 and VAR2: 1 to 128

Sweep type: Linear or logarithmic Sweep direction: Single or double sweep Hold Time: 0 to 655.35 s, 10 ms resolution Delay Time: 0 to 65.5350 s, 100 µs resolution

Pulsed Sweep Measurement Mode

This mode forces pulsed swept voltage or current, and measures DC voltage or current. A second channel can be programmed to output a staircase sweep voltage or current synchronized with the pulsed sweep output.

Staircase Sweep with Pulsed Bias Measurement Mode

This mode forces swept voltage or current, and measures DC voltage or current. A second channel can be programmed to output a pulsed bias voltage or current. A third channel can be synchronized with the primary sweep channel as an additional voltage or current sweep source.

Sampling (Time Domain) Measurement Mode

This mode displays the time sampled voltage/current data (by SMU) versus time.

- Sampling channels: up to 6 For sampling intervals < 2 ms, the number of sampling channels is 1
- Sampling points: 1 to 10,001/ (number of channels)
- Sampling mode: linear

Sampling interval range:

 $60 \ \mu s$ to 2 ms, 10 μs resolution 2 ms to $65.535 \ s$, 1 ms resolution

Hold time: -30 ms to -100 μs, 100 μs resolution

Bias hold time: 0 s

Bias Hold Function

This function is used to keep source output after measurement. Source modules apply the specified bias between measurements in a quick test or application test that defines some classic test setups, or a repeat measurement. Also, the source modules change the output value and the unused modules are disconnected when the next measurement is started.

Current Offset Cancel

This function subtracts the offset current from the current measurement raw data, and returns the result as the measurement data. It is used to compensate the error factor (offset current) caused by the measurement path such as the measurement cables, manipulators, or probe card.

Other Measurement Characteristics

Measurement Control: Single, Repeat, Append, and Stop

SMU Setting Capabilities: Limited auto ranging, voltage/ current compliance, power compliance, automatic sweep abort functions

Arithmetic and Analysis Functions

User Functions

Up to 20 user-defined functions can be defined using arithmetic expressions.

Measured data and pre-defined variables can be used in the computation, and the results can be displayed on the LCD.

Analysis Capabilities

Overlay Graph Comparison

A graphics plot can be stored and overlaid.

Scale

Auto scale and zoom

Marker

Marker to min/max, interpolation, direct marker, and marker skip

Cursor

Direct cursor

Line

Two lines, normal mode, grad mode, tangent mode, and regression mode

Automatic Analysis Function

On a graphics plot, the markers and lines can be automatically located using the auto analysis setup. Parameters can be automatically determined using automatic analysis, user function, and read out functions.

Data Variable Display

Up to 20 user-defined parameters can be displayed on the graphics screen.

Analysis Functions

Up to 20 user-defined analysis functions can be defined using arithmetic expressions. Measured data, pre-defined variables and read out functions can be used in the computation, and the results can be displayed on the LCD.

Read Out Functions

These built-in functions are for reading various values related to the marker, cursor, or line.

Graph Plot

Display Mode

The data display window can be printed. Only the X-Y graph can be printed.

Graph Plot File

The graph plot can be stored as image data to clip board or mass storage device. File type: bmp, gif, png, emf

Output

Display Modes

X-Y graph, list display, and parameter display

X-Y Graph Display

X-axis and up to eight Y-axis Linear and log scale Real time graph plotting

List Display

Measurement data and calculated user function data are listed in conjunction with VAR1 step number or time domain sampling step number. Up to 20 data sets can be displayed.

Other Functions

Import/Export files

File type:

Agilent EasyEXPERT format, XML-SS format, CSV format

System Requirements

The following are the minimum requirement for executing Desktop EasyEXPERT.

Processor: Intel Celeron 2 GHz Memory: 512 Megabytes DDR266 Display: XGA 1024 x 768 (SXGA

1280 x 1024 recommended) HDD: 1 GB free space on the C

Drive, 10 GB (30 GB recommended) free space on a drive for test setup/result data storage.

Supported GPIB Interfaces (for online mode):

	Agilent IO Libraries Suite 14.0	Agilent IO Libraries Suite 14.2
Agilent 82350B	Supported	Supported
Agilent 82357 A	Supported	Supported
Agilent 82357B	Not Supported	Supported

Operating System: Windows XP Professional SP2

Software:

Microsoft .NET Framework 1.1

Redistributable Package Microsoft .NET Framework 1.1 SP1 Agilent T&M Programmers Toolkit Redistributable Package 1.1 (Programmers Toolkit revision 2.0 is not supported.)

Supported 4155/4156 Parameter Analyzers

4155B, 4156B, 4155C, and 4156C Supported 4155/4156 firmware: HOSTC: 03.08 or later SMUC: 04.08 or later

Supported Auxiliary Instruments

Desktop EasyEXPERT Standard version

- Supported by switching matrix GUI: B2200A/B2201A
- Supported by application tests: E5250A (E5252A), 4284A/E4980A, 81110A, 3458A

Desktop EasyEXPERT Plus version

- All auxiliary instruments supported by EasyEXPERT Standard version
- Also supported by switching matrix GUI: E5250A (E5252A)

Setup Converter Tool

In addition to Desktop EasyEX-PERT, Agilent supplies a Setup File Converter tool that runs on any Windows-based PC. This tool can convert 4155 and 4156 measurement setup files (files of type "MES" and "DAT") into equivalent Desktop EasyEXPERT classic test mode setup files.

Attached Software

- Prober Control execution files Supported Probers:
 - Cascade Microtech Summit 12K or S300
- SUSS MicroTec PA200 or PA300

Vector Semiconductor VX-2000 or VX-3000

4155/56 setup file converter tool Supported operating systems: Microsoft Windows 2000 Professional and XP Home or Professional

Ordering Information

B1541A Agilent Desktop EasyEXPERT software and measurement libraries

B1541A-001

Agilent Desktop EasyEXPERT with license-to-use for standard version

B1541A-002

License-to-use for Agilent Desktop EasyEXPERT Plus For more information about Agilent and its products, go to www.agilent.com.

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Asia/Asia Pacific

Australia 1 800 629-485 China 1 800 276-3059 Hong Kong 852 2599 7889 India 91/11 690-6156 Japan 0120 421-345 Malaysia 1 800 880-780 New Zealand 0 800 738 378 Philippines 1 800 1651-0135 Singapore 1 800 276-3059 South Korea 080 778-0011 Taiwan 0 800 047-662 Thailand 1 800 2758-5822

Europe

Austria (01) 25 125-7183 Belgium (0) 2 404-9380 Denmark 080301040 Finland 20 547-9999 France (0) 825 010710 Germany (0) 18 05 24-63 34 Greece 20 547-9999 Ireland 016158393 Italy 02 92 60 8333 Luxembourg (0) 2 404-9340 Netherlands (0) 20 547-9999 Poland 20 547-9999 Russia 20 547-9999 Spain 91 631 3383 Sweden 020 120-9975 Switzerland (Italian) (0) 2 92 60 8484 Switzerland (German) (0) 1 735-9300 Switzerland (French) (0) 825 010 700 United Kingdom (0) 7004 222-222

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